

1. Record Nr.	UNINA9910146457403321
Titolo	2005 IEEE International Integrated Reliability Workshop final report : Stanford Sierra Conference Center, S. Lake Tahoe, California, October 17-20, 2005
Pubbl/distr/stampa	[Place of publication not identified], : IEEE Electron Devices Society, 2005
ISBN	1-5090-9773-2
Soggetti	Integrated circuits - Reliability Integrated circuits - Reliability - Wafer-scale integration
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph